

INFORMATION DISCLOSURE CITATION

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|------------------|--------------------------|------------|-----------------------------|------------|
| Atty. Docket No. | 04284.0878 | Serial No. | Not Yet Assigned | 10/765,122 |
| Applicants | Yasunobu YAMAUCHI et al. | | | |
| Filing Date | January 28, 2004 | Group: | Not Yet Assigned | 2624 |

U.S. PATENT DOCUMENTS

| Examiner Initial* | Document Number | Issue Date | Name | Class | Sub Class | Filing Date If Appropriate |
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| Examiner | /John Lee/ | Date Considered | 05/18/2007 |
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| Form PTO 1449 | Patent and Trademark Office - U.S. Department of Commerce | | |

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| IDS Form PTO/SB/08: Substitute for form 1449A/PTO | | | | Complete if Known | |
| | | | | Application Number | 10/765,122 |
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| | | | | First Named Inventor | Yasunobu Yamauchi |
| | | | | Art Unit | /JW 2624 |
| | | | | Examiner Name | /JW John W. Lee |
| | | | | Attorney Docket Number | 7906.0028 |
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Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

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|-------------------|-----------------------|---|--------------------------------|--|--|--------------------------|
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NON PATENT LITERATURE DOCUMENTS

| Examiner Initials ¹ | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | Translation ⁶ |
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| Examiner Signature | /John Lee/ | Date Considered | 05/18/2007 |
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